

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. <b>249746US2SDIV</b>		SERIAL NO. <b>New DIV Application</b>	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT <b>Hideo ANDO, et al.</b>			
				FILING DATE <b>Herewith</b>		GROUP <b>2616</b>	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
<i>DC</i>	AA	5,712,947	01/27/1998	<u>Oguro, et al.</u>	—	—	
<i>DC</i>	AB	6,385,389	05/07/02	<u>Maruyama, et al.</u>	—	—	
<i>DC</i>	AC	6,148,138	11/14/2000	Sawabe, et al.	—	—	
<i>DC</i>	AD	6,421,499	07/2002	Kim, et al.	—	—	
<i>DC</i>	AE	6,253,026	06/2001	Saeki, et al.	—	—	
<i>DC</i>	AF	6,389,222	05/2002	Ando, et al.	—	—	
<b>FOREIGN PATENT DOCUMENTS</b>							
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO			
<i>DC</i>	AG	EP 1 065 665 A1	01/03/2001	European Patent Office (in English)			
<i>DC</i>	AH	JP 5-165935	07/02/1993	JAPAN	X		
<i>DC</i>	AI	JP 5-81787	04/02/1993	JAPAN	X		
<i>DC</i>	AJ	JP 7-143429	06/02/1995	JAPAN	X		
<i>DC</i>	AK	JP 8-106721	04/23/1996	JAPAN	X		
<i>DC</i>	AL	JP 9-259539	10/03/1997	JAPAN	X		
<i>DC</i>	AM	JP 11-215471	08/06/1999	JAPAN (corresponding U.S. Patent no. 6,385,389 B1 <u>Maruyama, et al.</u> )		X	
<i>DC</i>	AN	JP 11-238362	08/31/1999	JAPAN (corresponding European Patent No. EP 1 065 665, <u>ANDO, et al.</u> )		X	
<i>DC</i>	AO	JP 5-158778	06/25/1993	JAPAN	X		
<i>DC</i>	AP	JP 5-165935	07/02/1993	JAPAN		X	
<i>DC</i>	AQ	JP 8-205014	08/09/1996	JAPAN	X		
<i>DC</i>	AR	JP 9-182013	07/11/1997	JAPAN	X		
<i>DC</i>		JP 11-136613	05/21/1999	JAPAN	X		
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
<i>DC</i>	AS	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-340033 (with English translation)					
<i>DC</i>	AT	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-340034 (with English translation)					
<i>DC</i>	AU	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-340035 (with English translation)					
<i>DC</i>	AV	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-340036 (with English translation)					
<i>DC</i>	AW	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-340037 (with English translation)					
	AX					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>Huy Nguyen</i>				Date Considered <i>11/10/04</i>			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>Me</i>	AA	6,353,702	03/2002	Ando, et al.	—	—	
<i>Me</i>	AB	5,687,160	11/1997	Aotake, et al.	—	—	
<i>Me</i>	AC	5,731,852	03/1998	Lee	—	—	
<i>Me</i>	AD	6,185,365	02/2001	Murase, et al.	—	—	
<i>Me</i>	AE	6,067,400	05/2000	Saeki, et al.	—	—	
<i>Me</i>	AF	6,526,226	02/2003	Kashiwagi, et al.	—	—	
	AG						
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<b>FOREIGN PATENT DOCUMENTS</b>							
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	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
<i>Me</i>	AW	<del>Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2002-87033 (w/English translation)</del>					
<i>Me</i>	AX	<del>Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1998-192063 (w/English translation)</del>					
<i>Me</i>	AY	<del>Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1999-256210 (w/English translation)</del>					
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <i>Deey Nguyen</i>					Date Considered <i>11/10/04</i>		
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